

AMENDMENT UNDER 37 C.F.R. §1.111
US Application No. 10/032,098
Attorney Docket No. Q67557

IN THE SPECIFICATION.

Please amend the following paragraphs of the Specification as follows:

Kindly amend paragraph [0003] of the written specification as follows:

[0003] This application is related to the commonly owned U.S. patent application Ser. No. 10/032,060, now issued as U.S. Patent No. 6,654,115 entitled "System and Method for Multi-Dimensional Optical Inspection", filed on the same date as this application, and commonly owned by Orbotech Ltd., the disclosure of said application being incorporated by reference, herein, in its entirety, for its useful example of a suitable mode for operation of a height attribute processor.

Kindly amend paragraph [0093] of the written specification as follows:

[0093] In accordance with an embodiment of the invention, the data acquired by sensor 620 is provided to an optical attribute processor 650 and to a height attribute processor 660. The optical attribute processor 650 is operative to detect defects based on analysis of an optical response, e.g. reflectance and/or fluorescence as known in the art. The height attribute processor 660 is operative to detect defects based on analysis of a height attribute. Height attribute processor 660 may operate on height information provided for an entire printed circuit board 16 under inspection. Optionally, because of the increased resources typically required to conduct height analysis, height attribute processor may operate only on those locations in a printed that are indicated as having suspected defects, for example based on inputs from illumination attribute processor. One suitable mode for operation of a height attribute processor 660 is described in U.S. ~~patent application Ser. No. _____~~ Patent No. 6,654,115, mentioned above in the "Related Applications" section of this disclosure, and entitled "System and Method for Multi-Dimensional Optical Inspection."

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Kindly amend paragraph [0096] of the written specification as follows:

[0096] Firstly, it is appreciated that multiple attribute processing may be used to increase reduce both the quantity of missed defects, namely real defects that are not detected, and to reduce the number of false alarms, namely non-defects that are falsely reported as defects. One way to achieve this result is to increase inspection sensitivity for inspection of a first attribute. This generally results in an increase in the number of reported defects, including falsely reported defects. However, in accordance with an embodiment of the invention, in combination with increasing the sensitivity of analysis of a first attribute, analysis of additional, typically independent, attributes is employed to reduce the number of false alarms.